Abstracts

Static Analysis of Microstrip Discontinuities Using the Excess Charge Density in the Spectral Domain

J. Martel, R.R. Boix and M. Horno. "Static Analysis of Microstrip Discontinuities Using the Excess Charge Density in the Spectral Domain." 1991 Transactions on Microwave Theory and Techniques 39.9 (Sep. 1991 [T-MTT] (Special Issue on Microwave Applications of Superconductivity)): 1623-1631.

Galerkin's method in the spectral domain is applied to solve for the excess charge density existing on the strips of open-end and symmetric gap discontinuities in multilayered anisotropic substrates. The excess charge density is used to determine the capacitance components of the equivalent circuits of these discontinuities. Numerical results are provided and a comparison with previous results existing in the literature is carried out.

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